

12/IDS 1-25-03

PATENT Docket No. 356952000304

#### CERTIFICATE OF MAILING BY "EXPRESS MAIL"

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Barbara M. Weatherk

### IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In the application of:

Kurt E. PETERSEN et al.

Serial No.:

09/928,194

Filing Date:

August 11, 2001

For:

SINGLE CRYSTAL SILICON SENSOR WITH HIGH ASPECT RATIO AND CURVILINEAR STRUCTURES AND

ASSOCIATED METHOD

Examiner: D. Kang

Group Art Unit: 2811

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SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. § 1.97 AND § 1.98

Assistant Commissioner for Patents Washington, D.C. 20231

Dear Sir:

Pursuant to 37 C.F.R. § 1.97 and § 1.98, Applicants submit for consideration in the above-identified application the documents listed on the attached Form PTO-1449. Copies of the documents are also submitted herewith. The Examiner is requested to make these documents of record.

04/18/2003 EHAILE1 00000032 031952 09928194

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This Su	ppleme	ntal Information Disclosure Statement is submitted:					
	Within three months of the application filing date or before mailing of a first						
	Office	Action on the merits; accordingly, no fee or separate requirements are					
	requir	ed.					
$\boxtimes$	After	receipt of a first Office Action on the merits but before mailing of a final					
	Office	e Action or Notice of Allowance.					
	$\boxtimes$	A fee is required. A check in the amount of is enclosed.					
	$\boxtimes$	A fee is required. Accordingly, a Fee Transmittal form (PTO/SB/17) is					
		attached to this submission in duplicate.					
		A Certification under 37 C.F.R. § 1.97(e) is provided below; accordingly;					
		no fee is believed to be due.					
	After	mailing of a final Office Action or Notice of Allowance, but before payment					
	of the	issue fee.					
		A Certification under 37 C.F.R. § 1.97(e) is provided below and a check in					
		the amount of is enclosed.					
		A Certification under 37 C.F.R. § 1.97(e) is provided below and a Fee					
-		Transmittal form (PTO/SB/17 is attached to this submission in duplicate.					

Applicants would appreciate the Examiner initialing and returning the Form PTO-1449, indicating that the information has been considered and made of record herein.

The information contained in this Supplemental Information Disclosure Statement under 37 C.F.R. § 1.97 and § 1.98 is not to be construed as a representation that: (i) a complete search has been made; (ii) additional information material to the examination of this application does

not exist; (iii) the information, protocols, results and the like reported by third parties are accurate or enabling; or (iv) the above information constitutes prior art to the subject invention.

In the unlikely event that the transmittal letter is separated from this document and the Patent Office determines that an extension and/or other relief is required, Applicants petition for any required relief including extensions of time and authorize the Assistant Commissioner to charge the cost of such petitions and/or other fees due in connection with the filing of this document to **Deposit Account No. 03-1952** referencing 356952000304. However, the Assistant Commissioner is not authorized to charge the cost of the issue fee to the Deposit Account.

Dated: April 15, 2003

Respectfully submitted,

By:

Christopher B. Eide Registration No. 48,375

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APR 1 5 2003

Form PTO-1449

# INFORMATION DISCLOSURE TATION IN AN APPLICATION

(Use several sheets if necessary)

	Sheet 1 of 2
Docket Number 356952000304	Application Number 09/928,194
Applicant	
Kurt E	. PETERSEN et al.
Filing Date August 11, 2001	Group Art Unit 2811

			U.S. PA	TENT DOCUMENTS		TC 28	<b>P</b> 70
Examiner Initials	Ref. No.	Date	Document No.	Name	Class	Subclass	=Biling Date If  △Appropriate
	1.	03/28/1995	5,400,824	Gschwendtner et al.		==	1VI
	i .					RC	

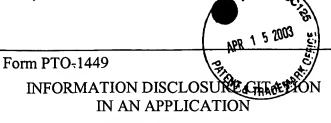
Mailing Date April 15, 2003

### FOREIGN PATENT DOCUMENTS

Examiner Initials	Ref. No.	Date	Document No.	Country	Class	Subclass	Translation YES NO
	2.	07/23/1992	41 01 575  Esp@ce summary of document only, located at < <http: ent.com="" gb.esp@c="">&gt;.</http:>	DE			x
	3.	11/23/1995	44 17 251  Esp@ce summary of document only, located at < <http: ent.com="" gb.esp@c="">&gt;.</http:>	DE			X
	4.	01/04/1996	44 22 942  Esp@ce summary of document only, located at < <http: ent.com="" gb.esp@c="">&gt;.</http:>	DE			Х

EXAMINER:	DATE CONSIDERED:

EXAMINER: Initial if citation considered, whether or not the citation conforms with MPEP 609. Draw a line through the citation if not in conformance and not considered. Include a copy of this form with next communication to applicant.



Docket Number 356952000304 Application Number 09/928,194

Applicant

Kurt E. PETERSEN et al.

Filing Date August 11, 2001 Group Art Unit 2811

(Use several sheets if necessary)

Mailing Date April 15, 2003

5.	08/20/1987	Esp@ce summary of document only, located at < <http: gb.esp@c<br="">ent.com&gt;&gt;.</http:>	JP		х	
6.	04/01/1999	WO 99/16096	WIPO			

## OTHER DOCUMENTS

(including author, title, Date, Pertinent Pages, Etc.)

Examiner Initials	Ref. No.	Title
	7.	Analog Devices, (1996). "Monolothic Accelerometer With Signal Conditioning," Analog Devices ADXL50 Datasheet Specifications. pp. 1-16.
	8.	Noworolski, J. M. et al. (1996). "Process for In-Plane and Out-of-Plane Single-Crystal-Silicon Thermal Microactuators," <i>Sensors and Acutuators</i> 55(1):65-69.
	9.	Seidel, H. et al. (1990). "Anisotropic Etching of Crystalline Silicon in Alkaline Solutions: I. Orientation Dependence and Behavior of Passivation Layers," <i>J. Electropchemica Soc.</i> 137(11):3612-3626.
	10.	Seidel, H. et al. (1990). "Anisotropic Etching of Crystalline Silicon in Alkaline Solutions: II. Influence of Dopants," J. Electropchemica Soc. 137(11):3626-3632.

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DATE CONSIDERED:

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